### INDEX TO ADVERTISERS

<table>
<thead>
<tr>
<th>Company</th>
<th>Page</th>
</tr>
</thead>
<tbody>
<tr>
<td>Diatome</td>
<td>Cover 3</td>
</tr>
<tr>
<td>EDAX</td>
<td>A7</td>
</tr>
<tr>
<td>Electron Microscopy Sciences, EMS</td>
<td>Cover 2</td>
</tr>
<tr>
<td>Hitachi</td>
<td>Cover 4</td>
</tr>
<tr>
<td>Physik Instrumente</td>
<td>A4</td>
</tr>
<tr>
<td>Tescan</td>
<td>A8</td>
</tr>
</tbody>
</table>
unsurpassed & unmatched...

Ultra-Wet 35° • Ultra-Dry 35°
Ultra-Semi 35° • Ultra Maxi 35°
Ultra Jumbo 35° • Ultra Sonic 35°
Ultra 35° • Ultra-AFM 35°
Ultra-Wet 45° • Ultra Jumbo 45°
Cryo 25° • Cryo Immuno 35°
Cryo-Dry 35° • Cryo-Wet 35°
Cryo-Dry 45° • Cryo-Wet 45° Cryo-AFM
Histo 45° • Histo Jumbo 45°
Histo-Cryo Dry 45° • Histo-Cryo Wet 45°
Trimtool 20 • Trimtool 45 • Static Line II

Need a bigger boat?...

DIATOME is still innovating. We are pleased to announce these latest additions to our line...

NEW

ultra Maxi

The ultra Maxi is similar to our ultra 35° 4.0 mm but with a larger boat. Thickness range: 30-200nm

NEW

ultra sonic Maxi

The ultra sonic Maxi is a new wider ultra sonic knife specifically for compression-free serial sectioning in biological applications. The knife comes in 3.0mm and 4.0mm sizes with 35° angle.

for more information, please visit our website at...

www.emsdiasum.com

DiATOME U.S.
P.O. Box 550 • 1560 Industry Rd.
Hatfield, PA 19440
Tel: (215) 412-8390
Fax: (215) 412-8450
email: info@emsdiasum.com
or stacie@ems-secure.com

ETHOS
Focused Ion and Electron Beam System

Aspire to Excellence

The Hitachi ETHOS SEM-FIB combines ultra-high resolution imaging and elemental analysis at low voltages with ion optics for nm-scale precision processing.

Designed with a variety of applications in mind
- Large analytical specimen chamber for numerous accessories
- Automated operation including macro processing
- Time sharing mode for dual simultaneous live imaging and processing
- Real-time analytical 3D segmentation capability

Advanced Microsampling
- Sample orientation control with Anti Curtaining Effect (ACE) technologies
- 4-axis lift-out function for advanced TEM specimen preparation

Triple-beam system yielding highest-quality results
- Low acceleration voltage processing with noble gas ion beam
- Selectable ion species (argon/xenon)

For more information, visit www.hitachi-hightech.com/us/fib

© Hitachi High-Tech America, Inc. microscopy@hitachi-hta.com Tel. 800-253-3053

www.hitachi-hightech.com/us

© 2020 Hitachi High-Tech America, Inc. All rights reserved.